

Search Notes

Application No.

10/084,947

Examiner

Paul L Kim

Applicant(s)

KAWAKITA ET AL.

Art Unit

2857

SEARCHED

Class	Subclass	Date	Examiner
702	181, 183	12/10/2003	PK
702	34, 35	12/11/2003	PK
702	42	12/11/2003	PK
73	812	12/11/2003	PK
703	2, 7	12/11/2003	PK

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Craig Miller	12/11/2003	PK
Google	12/11/2003	PK
Plus	6/18/2003	PK
Hal Wachsman	12/11/2003	PK
Jewell Thompson	12/11/2003	PK
Sam Broda	12/11/2003	PK
IEEE	12/11/2003	PK

	Hits	Search Text	DBs	Time Stamp
1	36	wire with flexure same life	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 11:14
2	6	wire with (test testing) with flexure	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 11:18
3	18	(wire with (test testing) same flexure) not (wire with (test testing) with flexure)	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 11:18
4	42	(wire with (test testing) same (bend bending)) and 73/\$.ccls.	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 11:27
5	146	(wire with (test testing) and (bend bending)) and 73/\$.ccls.	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 12:43
6	25	((wire with (test testing) and (bend bending)) and 73/\$.ccls.) and computer	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 14:06
7	63	((wire with (test testing) and strain) and 73/\$.ccls.) and computer	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 13:49
8	67	((cable with (test testing) and strain) and 73/\$.ccls.) and computer	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 13:49
9	18	((cable with (test testing) and (bend bending)) and 73/\$.ccls.) and computer) not ((cable with (test testing) and strain) and 73/\$.ccls.) and computer)	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 14:07
10	195	((wire cable) same (model modeling) same (test testing)) and (flex strain)	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 14:18
11	20	((wire cable) same (model modeling) same (test testing)) and (flex strain).ab.	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 14:38

	Hits	Search Text	Dbs	Time Stamp
12	124	(702/42).CCLS.	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 14:38
13	31	((702/42).CCLS.) and (cable wire)	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 14:56
14	70	((flex flexure strain) with (cable wire) same (model modeling)) and (computer microprocessor)	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 14:58
15	1	life adj estimation adj curve	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 16:39
16	17	((73/812).CCLS.) and (model modeling computer)	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 16:45
17	53	((703/2,7).CCLS.) and (flex flexure strain)	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 16:47
18	24	((702/34,35,181,183).CCLS.) and (wire cable).ab.	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 17:55
19	0	6163757.URPN.	USPAT	2003/12/11 18:38